Emil Manolov

List of Publications by Year in descending order

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Version: 2024-02-01

2258059 2272923 6 28 3 4 citations h-index g-index papers 6 6 6 51 docs citations all docs times ranked citing authors

#	Article	IF	CITATIONS
1	Application of Metal-Oxide-Semiconductor structures containing silicon nanocrystals in radiation dosimetry. Open Physics, 2015, 13, .	1.7	8
2	Formation of Si Nanocrystals in Thin SiO ₂ Films for Memory Device Applications. Materials Science Forum, 2010, 644, 101-104.	0.3	7
3	UV Sensitivity of MOS Structures with Silicon Nanoclusters. Sensors, 2019, 19, 2277.	3.8	7
4	Radiation Dosimeter Based on Metal-Oxide-Semiconductor Structures Containing Silicon Nanocrystals. Key Engineering Materials, 0, 495, 120-123.	0.4	5
5	Electrical Characterization of Interface Defects in MOS Structures Containing Silicon Nanoclusters. Advanced Materials Research, 2014, 976, 129-132.	0.3	1
6	Electrical Characterization of MOS Structures with Silicon Nanocrystals Suitable for X-Ray Detection. Key Engineering Materials, 0, 543, 150-153.	0.4	0